

## ABSTRACT:

A module (100) has test controller (140) for evaluating a functional block (120). The test controller (140) includes a first register (142) coupled between an input pin (162) and an output pin (164) from a plurality of pins (160) and a second register (144) coupled to the first register (142) for capturing an update of the content of the first register (142) responsive to an update signal from a decoder (170). The second register (144) is further arranged to generate evaluation control signals (145).

The test controller further includes dedicated control circuitry including a plurality of logic gates (180) and a first logic gate (182). The plurality of logic gates is arranged to decode the content of the first register (142) and provide the first logic gate (182) with a resulting gating signal for blocking the update of the second register (144). Consequently, the dedicated control circuitry is able to prevent undesired changes in the module (100) during an evaluation mode of for instance another module.

Fig. 1